PCN Num	ber:	20190		PCN Date: Sep 18, 2019						
Title:	1		rial change for Select Devices							
Customer Contact:			N Manager		Dept:		Qual	Quality Services		
				Estimated	•	e		provided at		
Proposed 1 st Ship Date:			c 18, 2019	Availabili				ple request.		
Change T	ype:							· · · · ·		
Assem	nbly Site		Assembly Pro		[ly Materials		
Desig			Electrical Spe					lechanical Specification		
Test S			Packing/Ship					est Process		
	Bump Site		Wafer Bump					Vafer Bump Process		
	Fab Site		Wafer Fab Materials				water F	ab Process		
Part number change PCN Details										
Descriptio	on of Change		PCN	Details						
			ne change to th	ne Die Coati	ng mater	ial fo	or the se	elected devices		
	roduct Affecte				ing mater	iai ie				
Die coating	g material diffe	erences (on top of top t	hick copper	metal lay	yer)	are note	ed below:		
	Chano	ge From	I			Cha	ange To			
		ONE					YIMID			
		vision: A			Di		evision:			
			·					_		
*No desigr	n change. Addi	tion of P	olyimide die co	ating only.						
		I in the C	<u>Qual Data Secti</u>	on.						
	or Change:									
- /	provement			0 111				/ X		
	ed impact on	Form, F	it, Function,	Quality or	Keliabili	ty (p	ositive	e / negative):		
None										
Changes t	to product id	entifica	tion resulting	from this	PCN:					
The Die Re	ev designator v	vill chang	ge as shown in	the table a	nd sample	e lab	el below	<i>ı</i> :		
Current	N	ew								
-	Die Rev [2P] Die Rev [2P]									
A D										
Sample product shipping label (not actual product label)										
INSTRUMENTS G4										
MADE IN: Malaysia 2DC: 20: (Q) 2000 (D) 0336										
MSL 2 /260C/1 YEAR SEAL DT (31T)LOT: 3959047MLA MSL 1 /235C/UNLIM 03/29/04 464 464 464 464 475 464 476 476 476 476 476 476 476 476 476										
OPT: ITEM:		9		(2P)		(V	0033			
	δA (L)T0:	ľ750		(20L)	CSO: SHE		L) CCO:	USA		
		100		(22L)	ASO: MLA	(2	3L) ACO:			
Droduct A	ffootod Crev	D 1								
	ADDRR	1		11002720	UCC27201ADRCR UCC27201ADRCT					
UCC27201	AUPKK	000272	01ADPRT	0002720	TADKCK		0002	/ ZUIADKUI		

Qualification Report

UCC27201A die with Polyimide coating (PI) Approve Date 12-Jun-2019

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>UCC27201ADP</u> <u>R</u>	Qual Device: <u>UCC27201ADR</u> <u>C</u>	QBS Product Reference: <u>UCC27201ADP</u> <u>R</u>	QBS Product Reference: <u>UCC27201ADR</u> <u>CT</u>	QBS Process Reference: <u>UCC27201AQD</u> <u>DARQ1</u>	QBS Process & Package Reference: <u>UCC27201AQD</u> <u>MKRQ1</u>	QBS Package Reference: <u>TPA5050RSA</u>	QBS Package Reference: <u>TPS61020DRC</u> <u>CU WIRE</u>
AC	Autoclave 121C	96 Hours	-	-	3/231/0	3/231/0	3/231/0	3/231/0	-	3/231/0
CDM	ESD - CDM - Q100	1500 Volts	-	-	-	-	1/3/0	1/3/0	-	-
CDM	ESD CDM	+/- 250, 500V	-	-	1/3/0	1/3/0	-	-	-	-
DS	Die Shear	-	1/Pass	1/Pass	1/Pass	1/Pass	1/Pass	1/Pass	1/10/0	3/30/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	1/Pass	1/Pass	3/90/0	3/90/0	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	-	3/2400/0	-	-	-
HAS T	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	3/231/0	3/231/0	1/80/0	-
HBM	ESD - HBM - Q100	1000 Volts	-	-	-	-	1/3/0	1/3/0	-	-
HTO L	Life Test, 125C	1000 Hours	-	-	-	-	3/231/0	1/77/0	-	-
HTO L	Life Test, 140C	480 Hours	-	-	-	-	-	-	1/116/0	-
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	1/45/0	1/77/0	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	-	-	-	-	3/231/0
LU	Latch-up	(per AEC- Q100-004)	-	-	-	-	1/6/0	1/6/0	-	-

Туре	Test Name / Condition	Duration	Qual Device: <u>UCC27201ADP</u> <u>R</u>	Qual Device: <u>UCC27201ADR</u> <u>C</u>	QBS Product Reference: <u>UCC27201ADP</u> <u>R</u>	QBS Product Reference: <u>UCC27201ADR</u> <u>CT</u>	QBS Process Reference: <u>UCC27201AQD</u> <u>DARQ1</u>	QBS Process & Package Reference: <u>UCC27201AQD</u> <u>MKRQ1</u>	QBS Package Reference: <u>TPA5050RSA</u>	QBS Package Reference: <u>TP S61020DRC</u> <u>CU WIRE</u>
PD	Physical Dimensions		-	-	-	-	-	3/30/0	1/5/0	3/15/0
PTC	Power Temperature Cycle, -40/125C	1000 Cycles	-	-	-	-	1/45/0	-	-	-
тс	Temperature Cycle, -65/150C	1000 Cycles	-	-	-	-	-	-	-	3/231/0
тс	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	3/231/0	3/231/0	3/231/0	-	3/261/0
TC- BP	Post TC Bond Pull	Wires	-	-	-	-	1/30/0	3/15/0	-	-
TS	Thermal Shock - 65/150C	1000 Cycles	-	-	-	-	-	-	-	3/231/0
TS	Thermal Shock - 65/150C	500 Cycles	-	-	-	-	-	-	-	3/231/0
WBP	Bond Pull	Wires	1/Pass	1/Pass	1/Pass	1/Pass	1/40/0	3/90/0	1/76/0	3/228/0
WBS	Bond Shear	Wires	1/Pass	1/Pass	1/Pass	1/Pass	1/40/0	3/90/0	1/76/0	3/228/0
YLD	Yield Evaluation	(per mfg. Site specification)	1/Pass	1/Pass	-	-	-	-	1/Pass	3/Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

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